Notice for TAIYO YUDEN products

Please read this notice before using the TAIYO YUDEN products.

/!\ REMINDERS

■ Product information in this catalog is as of October 2008. All of the contents specified herein are subject to change without notice due to technical improvements, etc. Therefore, please check for the latest information carefully before practical application or usage of the Products.

Please note that Taiyo Yuden Co., Ltd. shall not be responsible for any defects in products or equipment incorporating such products, which are caused under the conditions other than those specified in this catalog or individual specification.

- Please contact Taiyo Yuden Co., Ltd. for further details of product specifications as the individual specification is available.
- Please conduct validation and verification of products in actual condition of mounting and operating environment before commercial shipment of the equipment.
- All electronic components or functional modules listed in this catalog are developed, designed and intended for use in general electronics equipment. (for AV, office automation, household, office supply, information service, telecommunications, (such as mobile phone or PC) etc.). Before incorporating the components or devices into any equipment in the field such as transportation, (automotive control, train control, ship control), transportation signal, disaster prevention, medical, public information network (telephone exchange, base station) etc. which may have direct influence to harm or injure a human body, please contact Taiyo Yuden Co., Ltd. for more detail in advance.

Do not incorporate the products into any equipment in fields such as aerospace, aviation, nuclear control, submarine system, military, etc. where higher safety and reliability are especially required.

In addition, even electronic components or functional modules that are used for the general electronic equipment, if the equipment or the electric circuit require high safety or reliability function or performances, a sufficient reliability evaluation check for safety shall be performed before commercial shipment and moreover, due consideration to install a protective circuit is strongly recommended at customer's design stage.

- The contents of this catalog are applicable to the products which are purchased from our sales offices or distributors (so called "TAIYO YUDEN's official sales channel"). It is only applicable to the products purchased from any of TAIYO YUDEN's official sales channel.
- Please note that Taiyo Yuden Co., Ltd. shall have no responsibility for any controversies or disputes that may occur in connection with a third party's intellectual property rights and other related rights arising from your usage of products in this catalog. Taiyo Yuden Co., Ltd. grants no license for such rights.
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Certain items in this catalog may require specific procedures for export according to "Foreign Exchange and Foreign Trade Control Law" of Japan, "U.S. Export Administration Regulations," and other applicable regulations. Should you have any question or inquiry on this matter, please contact our sales staff.

Should you have any question or inquiry on this matter, please contact our sales staff.

般積層セラミックコンデンサ

(高誘電率系・Class 2)

STANDARD MULTILAYER CERAMIC CAPACITORS (CLASS2: HIGH DIELECTRIC CONSTANT TYPE)

	Code	Temp.characteristics	Operating temp. range			
OPERATING TEMP.	BJ	В	-25~+85°C			
	BJ	X5R*	-25~+85°C -55~+85°C -55~+125°C -25~+85°C			
	B7	X7R	-55~+125°C			
	F	F	-25~+85°C			
		Y5V	-30~+85°C			



^{*}個別仕様の取交しにより、X7R/X7S 仕様に対応している場合があります。

FEATURES

- ・実装密度の向上が図れます
- ・モノリシックの構造のため、信頼性が高い
- ・同一形状、静電容量範囲が広い

- · Improve Higher Mounting Densities.
- · Multilayer block structure provides higher reliability
- · A wide range of capacitance values available in standard case sizes.

用途 APPLICATIONS

- ·一般電子機器用
- ・通信機器用(携帯電話、PHS、コードレス電話 etc.)
- · General electronic equipment
- · Communication equipment (cellular phone, PHS, other wireless applications, etc.)

形名表記法 **ORDERING CODE**

1	
定格電	Œ〔VDC〕
Α	4
J	6.3
L	10
E	16
Т	25
G	35
U	50

2	
シリー	· ズ名
М	積層コンデンサ

2	
シリー	· ズ名
M	積層コンデンサ

メッキ品

端子電極

U

4	
形状寸法(E	$IA)L\times W(mm)$
042(01005)	0.4×0.2
063(0201)	0.6×0.3
105(0402)	1.0×0.5
	042(01005) 063(0201)

5	
温度特性	Ė
BJ	В
BJ	X5R
B7	X7R
ΔF	F
∠ F	Y5V
∧ = 7 ~ − 7	



容量許	容差
K	±10%
М	±20%
Z	+80 % -20 %
8	

8	
製品厚	[み (mm)
С	0.2
Р	0.3
V	0.5





1	
当社管	理記号
\triangle	標準
△=スペ-	- ス

LL_	IVI K	1,0,5	BJ	1,0,4	$_{\perp}$ K $_{\perp}$	V	_	
_					_	_		_

Rated	voltage(VDC)
Α	4
J	6.3
L	10
E	16
T	25
G	35

2	
Series name	
М	Multilayer ceramic
IVI	capacitor
_	

End termination

50

4									
Dimensions (case size) (L×W) (mm)									
042(01005)	0.4×0.2								
063(0201)	0.6×0.3								
105(0402)	1.0×0.5								

Temperature characteristics co									
BJ	В								
DJ	X5R								
B7	X7R								
△F	F								
△F	Y5V								
△ — Plank	20000								

Nominal capacitance (pF)									
example									
102	1000								
223	22000								

6

Capa	citance tolerance
K	± 10%
M	± 20%
Z	+80 % -20 %

Thickn	ess(mm)
С	0.2
P	0.3
V	0.5

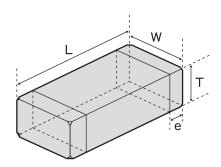
9	
Specia	al code
_	Standard products

10	
Packa	ging
F	φ 178mm Taping
г	(2mm pitch)

1	
Internal	code
	Standard Products
△=Blank	space

^{*}We may provide X7R/X7S for some items according to the individual specification.

EXTERNAL DIMENSIONS



Type (EIA)	L	W	Т		е		
☐MK042	0.4±0.02	0.2 ± 0.02	0.2±0.02	С	0.1±0.03		
(01005)	(0.016±0.001)	(0.008±0.001)	(0.008±0.001)	C	(0.004±0.001)		
☐MK063	0.6±0.03	0.3 ± 0.03	0.3±0.03	Р	0.15±0.05		
(0201)	(0.024±0.001)	(0.012±0.001)	(0.012±0.001)	Р	(0.006 ± 0.002)		
☐MK105	1.0±0.05*1	0.5±0.05*1	0.5±0.05*1		0.25±0.10		
(0402)	(0.039 ± 0.002)	(0.020 ± 0.002)	(0.020±0.002)	V	(0.010 ± 0.004)		
					Unit: mm (inch)		

注: *1 ±0.1mm 公差あり

Note: *1. Includding dimension tolerance ± 0.1 mm

概略バリエーション AVAILABLE CAPACITANCE RANGE

■汎用積層セラミックコンデンサ (General Multilayer Ceramic capacitors)

	Туре	0	42			0	63											105								
	Temp.char.	В/.	X5R		B/X5R			X5R			B/X7F	3			B/>	(5R				X5R				F/Y5V		
Cap	VDC																					Ī				l
[pF]	[pF:3digits]	10V	6.3V	25V	16V	10V	10V	6.3V	4V	50V	25V	16V	50V	35V	25V	16V	10V	6.3V	10V	6.3V	4V	50V	25V	16V	10V	6.3\
100	101																									
150	151																									
220	221																									
330	331	С		Р																						
470	471																									
680	681																									
1000	102																									
1500	152	_								V			V													
2200	222				Р																					
3300	332																									
4700	472		C																							
6800	682					Р																				
10000	103																					V				
15000	153										V															
22000	223					Р						37			V								V			
33000	333											V														
47000	473						Р	Р																V		
68000	683															V										
100000	104						Р	Р				V		V	V		1							V		
220000	224																V	V							V	
330000	334								Р																	
470000	474																		1/							
1000000	105																		V	V						V
2200000	225																									
3300000	335																				V					
4700000	475																				V					

注:グラフの記号は製品厚み記号です。Note: Letters in the table indicate thickness.

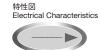
温度特性コード		Tem	静電容量許容差〔%〕	tanδ(%)				
Temp.char.Code		規格 e standard	温度範囲(℃) Temperature range	基準温度〔℃〕 Ref. Temp.	静電容量変化率〔%〕 Capacitance change	Capacitance tolerance	Dissipation factor	
B/BJ	JIS B		-25~+85	20	±10	1.40(16)		
D/DJ	EIA	X5R	-55~+85	25	±15	±10(K) ±20(M)	2.5 max.*	
B7	EIA	X7R	-55~+125	25	25 ±15			
	JIS F		-25~+85	20	+30/-80	+80 -20	7.0 max.*	
	EIA	Y5V	-30~+85	25	+22/-82	-20 ⁽²⁾	7.0 max."	

- *: 代表的な値を記載しています。詳細はアイテム一覧を参照ください。
- *: The figure indicate typical value. Please refer to PART NUMBERS table.



etc











アイテム一覧 PART NUMBERS

■ 042TYPE(01005 case size) -

【温度特性 Temp.char. BJ:B/X5R】

1/四/文/可工 1	emp.char. bo.b/xort							
定格電圧 Rated Voltage	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor (%) Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚み Thickness [mm] (inch)
	LMK042 BJ101 ☐ C	RoHS	100					
	LMK042 BJ151 ☐ C	RoHS	150		5		± 10% ± 20%	0.2 ± 0.02 (0.008 ± 0.001)
	LMK042 BJ221 ☐ C	RoHS	220					
10V	LMK042 BJ331 ☐ C	RoHS	330	B/X5R* ²				
	LMK042 BJ471 ☐ C	RoHS	470					
	LMK042 BJ681 ☐ C	RoHS	680					
	LMK042 BJ102 ☐ C	RoHS	1000			- R		
	JMK042 BJ152 ☐ C*1	RoHS	1500	D/XOIT				
	JMK042 BJ222 □ C*1	RoHS	2200					
6.3V	JMK042 BJ332 □ C*1	RoHS	3300		10			
0.37	JMK042 BJ472 □ C*1	RoHS	4700		10			
	JMK042 BJ682 □ C*1	RoHS	6800					
	JMK042 BJ103 □ C*1	RoHS	10000					

形名の□には静電容量許容差記号が入ります。

- *1 高温負荷試験の試験電圧は定格電圧の 1.5 倍
- *2 個別仕様の取交しにより、X7R/X7S仕様に対応している場合があります。
- ☐ Please specify the capacitance tolerance code.
- *1 Test Voltage of Loading at high temperature test is 1.5 time of the rated
- *2 We may provide X7R/X7S for some items according to the individual specification.

■ 063TYPE(0201 case size)

【温度特性 Temp.char. BJ:B/X5R】

[加汉付江]	emp.char. bJ.b/A3h]							
定格電圧 Rated Voltage	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor [%] Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚 み Thickness (mm) (inch)
	TMK063 BJ101□P	RoHS	100					
	TMK063 BJ151□P	RoHS	150					
	TMK063 BJ221□P	RoHS	220		3.5		±10% ±20%	
25V	TMK063 BJ331□P	RoHS	330					
	TMK063 BJ471□P	RoHS	470					0.3±0.03 (0.012±0.001)
	TMK063 BJ681□P	RoHS	680					
	TMK063 BJ102□P	RoHS	1000	B/X5R* ²				
	EMK063 BJ152□P	RoHS	1500	B/ASK		R		
	EMK063 BJ222□P	RoHS	2200					
	EMK063 BJ332□P	RoHS	3300		5			
	LMK063 BJ472□P	RoHS	4700					
	LMK063 BJ682□P	RoHS	6800					
40) (LMK063 BJ103□P	RoHS	10000					(0.012 ± 0.001)
10V	LMK063 BJ223□P*1	RoHS	22000		7.5			
	LMK063 BJ473□P*1	RoHS	47000		7.5			
	LMK063 BJ104□P* ¹	RoHS	100000		10			
	JMK063 BJ473□P* ¹	RoHS	47000		7.5			
6.3V	JMK063 BJ104□P* ¹	RoHS	100000	VED				
	JMK063 BJ224MP*1,*3	RoHS	220000	X5R				
	AMK063 BJ224MP*1	RoHS	220000		10		±20%	
4V	AMK063 BJ334MP*1,*3	RoHS	330000				±20%	
	AMK063 BJ474MP*1,*3	RoHS	470000					

形名の□には静電容量許容差記号が入ります。

- *1 高温負荷試験の試験電圧は定格電圧の 1.5 倍
- *2 個別仕様の取交しにより、X7R仕様に対応している場合があります。
- *3 ご使用の回路や機器により、個別仕様の取り交わしが必要になります。 必ず正規販売チャンネルにお問い合わせください。
- $\hfill \square$ Please specify the capacitance tolerance code.
- *1 Test Voltage of Loading at high temperature test is 1.5 time of the rated volt-
- *2 We may provide X7R for some items according to the individual specification.
- *3 The exchange of individual specification is necessary depending on the application and circuit condition. Please contact Taiyo Yuden sales channel.

■ 105TYPE(0402 case size)

【温度特性 Temp.char. BJ:B/X5R】

定格電圧 Rated Voltage	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor [%] Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚み Thickness 〔mm〕 (inch)
	UMK105 BJ221□V	RoHS	220					
	UMK105 BJ331□V	RoHS	330					
	UMK105 BJ471□V	RoHS	470					
	UMK105 BJ681□V	RoHS	680					
	UMK105 BJ102□V	RoHS	1000		2.5			
	UMK105 BJ152□V	RoHS	1500	B/X5R*2	2.5			
	UMK105 BJ222□V	RoHS	2200	1				
	UMK105 BJ332□V	RoHS	3300	.				
	UMK105 BJ472□V	RoHS	4700					
	UMK105 BJ682□V*1	RoHS	6800					
	UMK105 BJ103□V	RoHS	10000		3.5			0.5±0.05
35V	GMK105 BJ104□V*1	RoHS	100000	B/X5R	5			
	TMK105 BJ682□V	RoHS	6800		2.5			
	TMK105 BJ103□V	RoHS	10000					
	TMK105 BJ153□V	RoHS	15000	B/X5R* ²				
25V	TMK105 BJ223□V	RoHS	22000	B/X3H	3.5		±10%	
	TMK105 BJ333□V*1	RoHS	33000				±20%	
	TMK105 BJ473□V*1	RoHS	47000		В		(0.02 ± 0.002)	
	TMK105 BJ104□V*1	RoHS	100000	B/X5R	5	— R		
	EMK105 BJ333□V	RoHS	33000	B/X5R*2	0.5			
	EMK105 BJ473□V	RoHS	47000	B/X5R	3.5			
16V	EMK105 BJ683□V	RoHS	68000	B/X5R		-		
	EMK105 BJ104□V*1	RoHS	100000	B/X5R*2				
	EMK105 BJ224□V*1	RoHS	220000		5			
	LMK105 BJ104□V	RoHS	100000	B/X5R				
	LMK105 BJ224 V*1	RoHS	220000	1				
10V	LMK105 BJ474 V*1	RoHS	470000					
	LMK105 BJ105□V*1	RoHS	1000000	X5R	10			
	JMK105 BJ224□V*1	RoHS	220000	B/X5R	5			
	JMK105 BJ474□V*1	RoHS	470000					
6.3V	JMK105 BJ105□V* ¹	RoHS	1000000	1				
	JMK105 BJ225MV* ^{1,*3}	RoHS	2200000					1
	AMK105 BJ335MV* ^{1,*3}	RoHS	3300000	X5R	10		1.0007	
4V	AMK105 BJ475MV* ^{1,*3}	RoHS	4700000	-			±20%	0.5±0.1 (0.02±0.00

形名の□には静電容量許容差記号が入ります。

- *2 We may provide X7R for some items according to the individual specification.
- $^{\star}3$ The exchange of individual specification is necessary depending on the application and circuit condition. Please contact Taiyo Yuden sales channel.

^{*1} 高温負荷試験の試験電圧は定格電圧の 1.5 倍

^{*2} 個別仕様の取交しにより、X7R仕様に対応している場合があります。

^{*3} ご使用の回路や機器により、個別仕様の取り交わしが必要になります。 必ず正規販売チャンネルにお問い合わせください。

 $[\]hfill \square$ Please specify the capacitance tolerance code.

^{*1} Test Voltage of Loading at high temperature test is 1.5 time of the rated volt-

アイテム一覧 PART NUMBERS

【温度特性 Temp.char. B7:X7R】

E		 						
定格電圧 Rated Voltage	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor [%] Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚 み Thickness 〔mm〕 (inch)
	UMK105 B7221□V	RoHS	220					
	UMK105 B7331□V	RoHS	330					
	UMK105 B7 471□V	RoHS	470				±10% ±20%	
	UMK105 B7681□V	RoHS	680					
	UMK105 B7 102□V	RoHS	1000		0.5			0.5 ± 0.05 (0.02 ± 0.002)
50V	UMK105 B7 152□V	RoHS	1500		2.5			
	UMK105 B7222□V	RoHS	2200					
	UMK105 B7332□V	RoHS	3300					
	UMK105 B7 472 UV*1	RoHS	4700					
	UMK105 B7682□V*1	RoHS	6800					
	UMK105 B7 103 □ V*1	RoHS	10000		3.5			
	TMK105 B7 472 UV	RoHS	4700	X7R	2.5	R		
	TMK105 B7 682□V	RoHS	6800		2.5			
	TMK105 B7 103□V	RoHS	10000					
25V	TMK105 B7 153 □ V*1	RoHS	15000					
	TMK105 B7223 □ V*1	RoHS	22000					
	TMK105 B7333□V* ¹	RoHS	33000					
	TMK105 B7 473 □ V*1	RoHS	47000		3.5			
	EMK105 B7 153□V	RoHS	15000					
	EMK105 B7223□V	RoHS	22000					
16V	EMK105 B7333□V	RoHS	33000]				
	EMK105 B7473□V	RoHS	47000					
	EMK105 B7 104□V*1	RoHS	100000		5			

形名の□には静電容量許容差記号が入ります。

【温度特性 Temp.char. F:Y5V】

定格電圧 Rated Voltage	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor (%) Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚み Thickness (mm) (inch)
50V	UMK105 F103ZV	RoHS	10000		5			
25V	TMK105 F223ZV	RoHS	22000		5	_	+80%	0.5.1.0.05
16V	EMK105 F473ZV	RoHS	47000		7			
100	EMK105 F104ZV	RoHS	100000	F/Y5V	9	R		0.5 ± 0.05
10V	LMK105 F224ZV	RoHS	220000		11]	-20%	(0.02 ± 0.002)
6.01/	JMK105 F474ZV	RoHS	470000		12.5			
6.3V	JMK105 F105ZV*1	RoHS	1000000		20			

^{*1} 高温負荷試験の試験電圧は定格電圧の 1.5 倍

^{*1} 高温負荷試験の試験電圧は定格電圧の 1.5 倍

 $[\]square$ Please specify the capacitance tolerance code.

^{*1} Test Voltage of Loading at high temperature test is 1.5 time of the rated voltage.

^{*1} Test Voltage of Loading at high temperature test is 1.5 time of the rated voltage.

梱包 PACKAGING

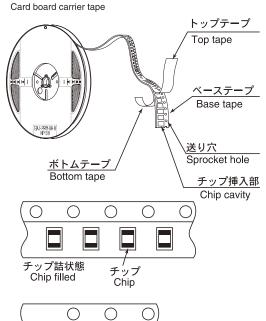
①最小受注単位数 Minimum Quantity

■テーピング梱包 Taped packaging

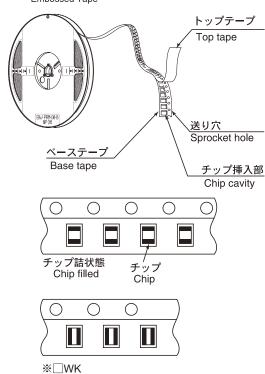
	raped packaging			
形式(EIA) Type	製品厚み Thickness			数量 d quantity s]
Турс	mm(inch)	code	紙テープ paper	エンボステープ Embossed tape
☐MK042 (01005)	0.2(0.008)	С	15000	—
☐MK063(0201)	0.3 (0.012)	Р	15000	_
□2K096(0302)	0.3(0.012)	Р	10000	
2KU96(U3U2)	0.45 (0.018)	K	10000	_
□WK105 (0204)	0.3(0.012)	Р	10000	_
☐MK105(0402)	0.5(0.020)	V, W	10000	
□VK105 (0402)	0.5(0.020)	W	10000	_
	0.45 (0.018)	K	4000	_
☐MK107(0603) ☐WK107(0306)	0.5 (0.020)	V	_	4000
VVK107(0300)	0.8(0.031)	Α	4000	_
	0.5(0.020)	V	4000	_
□2K110(0504)	0.8(0.031)	Α	4000	_
	0.6(0.024)	В	4000	_
□MI(040(0005)	0.45 (0.018)	K	4000	
☐MK212(0805) ☐WK212(0508)	0.85 (0.033)	D	4000	_
	1.25 (0.049)	G	_	3000
☐4K212(0805)	0.85 (0.033)	D	4000	_
□2K212(0805)	0.85 (0.033)	D	4000	_
	0.85 (0.033)	D	4000	
	1.15 (0.045)	F		3000
□MK316(1206)	1.25 (0.049)	G	_	3000
	1.6 (0.063)	L	_	2000
	0.85 (0.033)	D		
	1.15 (0.045)	F		2000
□MK325(1210)	1.5 (0.059)	Н		2000
_IVIK323(1210)	1.9(0.075)	N		
	2.0max (0.079)	Υ	_	2000
	2.5(0.098)	М	_	500(T), 1000(P)
☐MK432(1812)	2.5(0.098)	М	_	500

②テーピング材質 Taping material 紙テープ

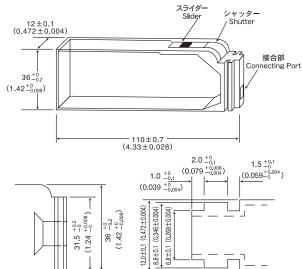
※プレスポケットタイプは、 ボトムテープ無し。



エンボステープ **Embossed Tape**



③バルクカセット Bulk Cassette



105, 107, 212形状で個別対応致しますのでお問い合せ下さい。 Please contact any of our offices for accepting your requirement according to dimensions 0402, 0603, 0805.(inch)

Unit: mm (inch)

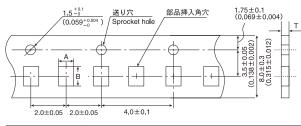
 $\#\square WK$

③テーピング寸法 Taping dimensions 紙テープ Paper Tape (8mm幅) (0.315inches wide)

1.5^{+0.1} 送り穴 部品挿入角穴 (0.069±0.004) Sprocket hole (0.059±0.004) Sprocket hole (0.059±0.004) T (0.069±0.004) T

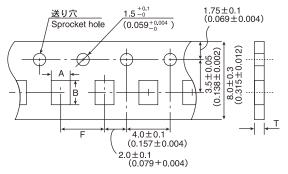
Туре (Е I A)			挿入ピッチ Insertion Pitch	テープ厚み Tape Thickness		
(LTA)	А	В	F	Т	T1	
☐MK042(01005)	0.25 0.45 (0.018) (0.018)		2.0±0.05 (0.079±0.002) 0.36max. (0.014)		0.27max. (0.011)	
☐MK063(0201)	MK063(0201) 0.37 0.67 (0.016) (0.027)		2.0±0.05 (0.079±0.002)	0.45max. (0.018)	0.42max. (0.017)	
□WK105(0204)	0.65 (0.026)	1.15 (0.045)	2.0±0.05 (0.079±0.002)	0.45max (0.018max)	0.42max (0.017max)	

Unit: mm (inch)



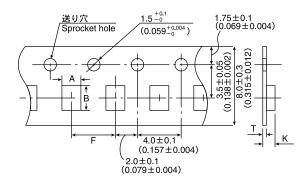
T	チッフ	『挿入部	挿入ピッチ	テープ厚み	
Type (EIA)	Chip (Cavity	Insertion Pitch	Tape Thickness	
(EIA)	Α	В	F	Т	
	0.72	1.02	2.0±0.05	0.45max.(0.018max)	
□2K096(0302)	(0.028)	(0.040)	(0.079±0.002)	0.6max.(0.024max)	
☐MK105(0402)	0.65	1.15	2.0±0.05	0.8max.	
□VK105 (0402)	(0.026)	(0.045)	(0.079±0.002)	(0.031max.)	

Unit: mm (inch)



Time	チッフ	°挿入部	挿入ピッチ	テープ厚み	
Type	Chip (Cavity	Insertion Pitch	Tape Thickness	
(EIA)	Α	В	F	Т	
☐MK107(0603)	1.0	1.8	4.0±0.1	1.1max.	
□WK107(0306)	(0.039)	(0.071)	(0.157±0.004)	(0.043max.)	
	1.15	1.55	4.0±0.1	1.0max.	
□2K110 (0504)	(0.045)	(0.061)	(0.157±0.004)	(0.039max.)	
☐MK212(0805)					
□WK212 (0508)	1.65	2.4			
□4K212 (0805)	(0.065)	(0.094)	4.0±0.1	1.1max.	
□2K212(0805)			(0.157±0.004)	(0.043max.)	
	2.0	3.6			
□MK316 (1206)	(0.079)	(0.142)			

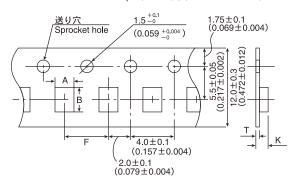
エンボステープ Embossed tape (8mm幅) (0.315inches wide)



Tuna	チップ	°挿入部	挿入ピッチ	テープ厚み	
Type	Chip	cavity	Insertion Pitch	Tape Thickness	
(EIA)	Α	В	F	K	Т
	1.0	1.8		1.3max.	0.25±0.1
□WK107 (0306)	(0.039)	(0.071)		(0.051max.)	(0.01±0.004)
	1.65	2.4			
□MK212 (0805)	(0.065)	(0.094)	4.0±0.1		
	2.0	3.6	(0.157±0.004)	3.4max.	0.6max.
□MK316 (1206)	(0.079)	(0.142)		(0.134max.)	(0.024max.)
	2.8	3.6			
☐MK325 (1210)	(0.110)	(0.142)			

Unit: mm (inch)

エンボステープ Embossed tape (12mm幅) (0.472inches wide)

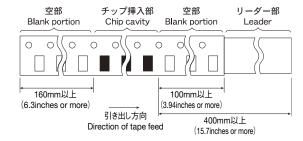


_	チップ	[°] 挿入部	挿入ピッチ	テープ厚み			
Type	Chip	cavity	Insertion Pitch	Tape Th	ickness		
(EIA)	А	В	F K		Т		
☐MK432 (1812)	32 (1812) 3.7 4.9 (0.146) (0.19		8.0±0.1 (0.315±0.004)	4.0max. (0.157max.)	0.6max. (0.024max.)		
Unit: mm (inch)							

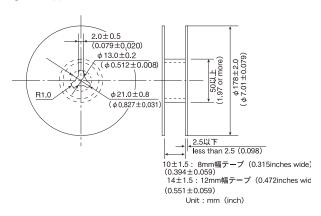
Unit: mm (inch)

梱包 PACKAGING

④リーダー部/空部 Leader and Blank portion

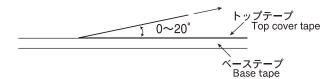


⑤リール寸法 Reel size



⑥トップテープ強度 Top Tape Strength

トップテープのはがし力は下図矢印方向にて0.1~0.7Nとなります。 The top tape requires a peel-off force of $0.1 \sim 0.7 N$ in the direction of the arrow as illustrated below.



Multilayer Ceramic Capacitor Chips

			Specific	ed Value		
It	tem	Temperature Comp	pensating (Class 1)	High Permitiv	vity (Class 2)	Test Methods and Remarks
		Standard	High Frequency Type	Standard Note1	High Value	
1.Operating Range	Temperature	-55 to +125°C		BJ: −55 to +125°C F: −25 to +85°C	−25 to +85°C	High Capacitance Type BJ (X7R): -55~+125°C, BJ (X5R): -55~+88 E (Y5U): -30~+85°C, F (Y5V): -30~+88°
2.Storage Temperature Range		−55 to +125°C		F: −25 to +85°C		$\begin{tabular}{lllllllllllllllllllllllllllllllllll$
3.Rated Volta	ge	50VDC,25VDC, 16VDC	16VDC 50VDC	50VDC,25VDC	50VDC,35VDC,25VDC 16VDC,10VDC,6.3VDC 4DVC, 2.5VDC	
Withstanding Voltage Between terminals		No breakdown or damage	No abnormality			Applied voltage: Rated voltage ×3 (Class 1) Rated voltage ×2.5 (Class 2) Duration: 1 to 5 sec. Charge/discharge current: 50mA max. (Class 1,2)
5.Insulation R	Resistance	10000 MΩ min.		500 M Ω μ F. or 10000 smaller.	$M\Omega$., whichever is the	Applied voltage: Rated voltage Duration: 60±5 sec. Charge/discharge current: 50mA max.
6.Capacitance	e (Tolerance)	0.5 to 5 pF: ±0.25 pF 1 to 10 pF: ±0.5 pF 5 to 10 pF: ±1 pF 11 pF or over: ±5% ±10% 105TYPERA, SA, TA, UA only 0.5~2pF: ±0.1pF 2.2~20pF: ±5%	0.5 to 2 pF : ±0.1 pF 2.2 to 5.1 pF : ±5%	BJ: ±10%, ±20% F: +80% -20%	BJ: ±10%、±20% F: -20%/+80%	Measuring frequency: Class1: $1 \text{MHz} \pm 10\%$ (C≤1000pF) $1 \text{ kHz} \pm 10\%$ (C>1000pF) $1 \text{ kHz} \pm 10\%$ (C>1000pF) Class2: $1 \text{ kHz} \pm 10\%$ (C≤10 μ F) $120 \text{Hz} \pm 10 \text{Hz}$ (C>10 μ F) Measuring voltage: Note 4 Class1: $0.5 \sim 5 \text{Vrms}$ (C≤1000pF) $1 \pm 0.2 \text{Vrms}$ (C>1000pF) Class2: $1 \pm 0.2 \text{Vrms}$ (C≤10 μ F) $0.5 \pm 0.1 \text{Vrms}$ (C>10 μ F) Bias application: None
7.Q or Tangen (tan δ)	t of Loss Angle	Under 30 pF : Q≥400 + 20C 30 pF or over : Q≥1000 C= Nominal capacitance	Refer to detailed specification	BJ: 2.5% max. (50V, 25V) F: 5.0% max. (50V, 25V) Note 4	BJ: 2.5% max. F: 7% max. Note 4	$\begin{array}{lll} & \text{Multilayer:} \\ & \text{Measuring frequency:} \\ & \text{Class1:} & 1 \text{MHz} \pm 10\% & (C \leq 1000 \text{pF}) \\ & 1 \text{ k Hz} \pm 10\% & (C > 1000 \text{pF}) \\ & \text{Class2:} & 1 \text{ k Hz} \pm 10\% & (C \leq 10 \mu \text{F}) \\ & 120 \text{Hz} \pm 10 \text{Hz} & (C > 10 \mu \text{F}) \\ & \text{Measuring voltage:} \\ & \text{Note 4} & \text{Class1:} & 0.5 \sim 5 \text{Vrms} & (C \leq 1000 \text{pF}) \\ & 1 \pm 0.2 \text{Vrms} & (C > 1000 \text{pF}) \\ & \text{Class2:} & 1 \pm 0.2 \text{Vrms} & (C \leq 10 \mu \text{F}) \\ & \text{Class2:} & 1 \pm 0.2 \text{Vrms} & (C > 10 \mu \text{F}) \\ & \text{Bias application: None} \\ & \text{High} - \text{Frequency} - \text{Multilayer:} \\ & \text{Measuring frequency:} & \text{1GHz} \\ & \text{Measuring equipment:} & \text{HP4291A} \\ & \text{Measuring jig:} & \text{HP16192A} \\ \end{array}$
8.Temperature Characteristic of Capacitance	(Without voltage ap- plication)	CK: 0±250 CJ: 0±120 CH: 0±60 CG: 0±30 RH: -220±60 SK: -330±250 SJ: -330±120 SH: -330±60 TK: -470±250 TJ: -470±120 UK: -750±250 UJ: -750±120 SL: +350 to -1000 (ppm/C)	CH:0±60 RH:-220±60 (ppm/C)	BJ: ±10% (-25~85°C) F: +30% (-25~85°C) BJ (X7R): ±15% F (Y5V): +22% -82	BJ: ±10% (-25~+85°C) F: +30%/-80% (-25~+85°C) BJ (X7R, X5R): ±15% F (Y5V): +22%/-82%	According to JIS C 5102 clause 7.12. Temperature compensating: Measurement of capacitance at 20°C and 85°C shall made to calculate temperature characteristic by the following equation. $\frac{(C_{65}-C_{20})}{C_{20}\times\triangle T}\times 10^{6} (\text{ppm/°C})$ High permitivity: Change of maximum capacitance deviation in step 1 to Temperature at step 1: $+20^{\circ}\text{C}$ Temperature at step 2: minimum operating temperature Temperature at step 3: $+20^{\circ}\text{C}$ (Reference temperature Temperature at step 5: $+20^{\circ}\text{C}$ Reference temperature for X7R, X5R, Y5U and Y5V shall be $+25^{\circ}$
9.Resistance Substrate	to Flexure of	Appearance: No abnormality Capacitance change: Within ±5% or ±0.5 pF, whichever is larger.	Appearance: No abnormality Capacitance change: Within±0.5 pF	Appearance: No abnormality Capacitance change: BJ: Within ±12.5% F: Within ±30%		Warp: 1mm Testing board: glass epoxy—resin substrate Thickness: 1.6mm (063 TYPE : 0.8mm) The measurement shall be made with board in the bent positio Board R-230 Warp Warp (Unit: mm)

Multilayer Ceramic Capacitor Chips

		Specifie	ed Value				
Item	Temperature Comp	ensating (Class 1)	High Permitti	vity (Class 2)	Test Methods and Remarks		
	Standard	High Frequency Type	Standard Note1	High Value			
10.Body Strength	_	No mechanical damage.	_	_	High Frequency Multilayer: Applied force: 5N Duration: 10 sec. Press Pressing jie Chip (LW Reverse)		
1.Adhesion of Electrode	No separation or indicat	ion of separation of elect	rode.		Applied force: 5N Duration: 30±5 sec. (01005, 0201, 0302 TYPE 2N) Hooked jig R=05 Chip Cross-section		
12.Solderability	At least 95% of termina	electrode is covered by	new solder.		Solder temperature: 230±5℃		
13.Resistance to soldering	Appearance: No abnormality Capacitance change: Within ±2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals):	Appearance: No abnormality Capacitance change: Within ±2.5% Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	tan δ: Initial value Insulation resistance: Ini	Vithin ±7.5% (BJ) Vithin ±20% (F) Note 4	Duration: 4±1 sec. Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Solder temperature: 270±5°C Duration: 3±0.5 sec. Preheating conditions: 80 to 100°C, 2 to 5 min. or 5 to 10 min. 150 to 200°C, 2 to 5 min. or 5 to 10 min. Recovery: Recovery for the following period under the standard condition after the test. 6~24 hrs (Class 1) 24±2 hrs (Class 2)		
14.Thermal shock	Appearance: No abnormality Capacitance change: Within ±2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±0.25pF Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within $\pm 7.5\%$ (BJ) Within $\pm 20\%$ (F) tan δ : Initial value Note 4 Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality		Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Conditions for 1 cycle: Step 1: Minimum operating temperature $^{+0}_{-3}$ °C 30±3 min Step 2: Room temperature 2 to 3 min Step 3: Maximum operating temperature $^{-0}_{+3}$ °C 30±3 min Step 4: Room temperature 2 to 3 min Step 4: Room temperature 2 to 3 min Step 4: Room temperature 2 to 3 min Number of cycles: 5 times Recovery after the test: 6~24 hrs (Class 1) 24±2 hrs (Class 2)		
15.Damp Heat (steady state)	Appearance: No abnormality Capacitance change: Within $\pm 5\%$ or $\pm 0.5 pF$, whichever is larger. Q: C ≥ 30 pF : Q ≥ 350 $10 \leq C < 30$ pF: Q $\geq 275 + 2.5 C$ C<10 pF : Q ≥ 200 + 10C C: Nominal capacitance Insulation resistance: 1000 M Ω min.	Appearance: No abnormality Capacitance change: Within $\pm 0.5 \text{pF}$, Insulation resistance: $1000 \text{ M}\Omega$ min.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ tan δ : BJ: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: $50~\mathrm{M}\Omega~\mu\mathrm{F}$ or $1000~\mathrm{M}\Omega$ whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ:Within $\pm 12.5\%$ Note 4 $\tan \delta$: BJ: 5.0% max. Note 4. F: 11.0% max. Insulation resistance: $50~\mathrm{M}\Omega\mu\mathrm{F}$ or $1000~\mathrm{M}\Omega$ whichever is smaller. Note 5	Multilayer: Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Temperature: 40±2°C Humidity: 90 to 95% RH Duration: 500 +24 hrs Recovery: Recovery for the following period under the standard condition after the removal from test chamber. 6~24 hrs (Class 1) 24±2 hrs (Class 2) High—Frequency Multilayer: Temperature: 60±2°C Humidity: 90 to 95% RH Duration: 500 +24 hrs Recovery: Recovery for the following period under the standard condition after the removal from test chamber. 6~24 hrs (Class 1)		

Multilayer Ceramic Capacitor Chips

	Specified Value				
Item	Temperature Compensating (Class 1)		High Permittivity (Class 2)		Test Methods and Remarks
	Standard	High Frequency Type	Standard Note1	High Value	
16.Loading under Damp Heat	Appearance: No abnormality Capacitance change: Within ±7.5% or ± 0.75pF, whichever is larger. Q: C≧30 pF: Q≧200 C<30 pF: Q≧100 + 10C/3 C: Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: C≦2 pF: Within ±0.4 pF C>2 pF: Within ±0.75 pF C: Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : BJ: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: $25~\rm M\Omega\mu F$ or 500 MΩ, whichever is the smaller. Note 5	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 $\tan \delta$: BJ: 5.0%max. F: 11%max. Note 4 Insulation resistance: $25~\mathrm{M}\Omega~\mu\mathrm{F}$ or 500 M Ω , whichever is the smaller. Note 5	According to JIS C 5102 Clause 9. 9. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature: 40±2°C Humidity: 90 to 95% RH Duration: 500 +24°hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. (Class 1,2) Recovery: Recovery for the following period under the standard condition after the removal from test chamber. 6~24 hrs (Class 1) 24±2 hrs (Class 2) High—Frequency Multilayer: Temperature: 60±2°C Humidity: 90 to 95% RH Duration: 500 +24°hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. Recovery: 6~24 hrs of recovery under the standard condition after the removal from test chamber
17.Loading at High Temperature	Appearance: No abnormality Capacitance change: Within $\pm 3\%$ or ± 0.3 pF, whichever is larger. Q: C ≥ 30 pF : Q ≥ 275 + 2.5C C < 10 pF: Q ≥ 200 + 10C C: Nominal capacitance Insulation resistance: 1000 M Ω min.	Appearance: No abnormality Capacitance change: Within $\pm 3\%$ or \pm 0.3pF, whichever is larger. Insulation resistance: 1000 M Ω min.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : BJ: 4.0% max. F: 7.5% max. Note 4 Insulation resistance: $50~\mathrm{M}\Omega~\mu\mathrm{F}$ or $1000~\mathrm{M}\Omega$, whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ Within $\pm 20\%\%\%$ F: Within $\pm 25\%\%\%$ F: Within $\pm 30\%$ Note 4 $\tan \delta$: BJ: 5.0%max. F: 11%max. Note 4 Insulation resistance: $50~\mathrm{M}\Omega\mu\mathrm{F}$ or $1000~\mathrm{M}\Omega$, whichever is smaller. Note 5	According to JIS C 5102 clause 9.10. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature:125±3°C (Class 1, Class 2: B, BJ (X7R)) 85±2°C (Class 2: BJ,F) Duration: 1000 ⁺⁴⁶ hrs Applied voltage: Rated voltage ×2 Note 6 Recovery: Recovery for the following period under the standard condition after the removal from test chamber. 6~24 hrs (Class 1) 24±2 hrs (Class 2) High—Frequency Multilayer: Temperature: 125±3°C (Class 1) Duration: 1000 ⁺⁴⁶ hrs Applied voltage: Rated voltage×2 Recovery: 6~24 hrs of recovery under the standard condition after the removal from test chamber

Note 1 :For 105 type, specified in "High value".

Note 2 :Thermal treatment (Multilayer): 1 hr of thermal treatment at 150 + 0 / - 10 °C followed by 24±2 hrs of recovery under the standard condition shall be performed before the measurement. Voltage treatment (Multilayer): 1 hr of voltage treatment under the specified temperature and voltage for testing followed by 24±2 hrs of recovery under the standard condition shall be performed before the measurement. Note 4, 5 : The figure indicates typical inspection. Please refer to individual specifications.

Note 6 :Some of the parts are applicable in rated voltage × 1.5. Please refer to individual specifications.

Note on standard condition: "standard condition" referred to herein is defined as follows: 5 to 35°C of temperature, 45 to 85% relative humidity, and 86 to 106kPa of air pressure. Unless otherwise specified, all the tests are conducted under the "standard condition."

Stages	Precautions	Technical considerations
1.Circuit Design	Verification of operating environment, electrical rating and performance 1. A malfunction in medical equipment, spacecraft, nuclear reactors, etc. may cause serious harm to human life or have severe social ramifications. As such, any capacitors to be used in such equipment may require higher safety and/or reliability considerations and should be clearly differentiated from components used in general purpose applications. Operating Voltage (Verification of Rated voltage) 1. The operating voltage for capacitors must always be lower than their rated values. If an AC voltage is loaded on a DC voltage, the sum of the two peak voltages should be lower than the rated value of the capacitor chosen. For a circuit where both an AC and a pulse voltage may be present, the sum of their peak voltages should also be lower than the capacitor's rated voltage. 2. Even if the applied voltage is lower than the rated value, the reliability of capacitors might be reduced if either a high frequency AC voltage or a pulse voltage having rapid rise time is present in the circuit.	
2.PCB Design	Pattern configurations (Design of Land-patterns) 1. When capacitors are mounted on a PCB, the amount of solder used (size of fillet) can directly affect capacitor performance. Therefore, the following items must be carefully considered in the design of solder land patterns: (1) The amount of solder applied can affect the ability of chips to withstand mechanical stresses which may lead to breaking or cracking. Therefore, when designing land-patterns it is necessary to consider the appropriate size and configuration of the solder pads which in turn determines the amount of solder necessary to form the fillets. (2) When more than one part is jointly soldered onto the same land or pad, the pad must be designed so that each component's soldering point is separated by solder-resist.	1.The following diagrams and tables show some examples of recommended patterns to prevent excessive solder amourts. (larger fillets which extend above the component end terminations) Examples of improper pattern designs are also shown. (1) Recommended land dimensions for a typical chip capacitor land patterns for PCBs Land pattern Chip capacitor Chip capacitor Chip capacitor Chip capacitor Chip capacitor W Recommended land dimensions for wave-soldering (unit: mm) Type 107 212 316 325 Land pattern Chip capacitor Chip capacitor Size L 1.6 2.0 3.2 3.2 W 0.8 1.25 1.6 2.5 A 0.8~1.0 1.0~1.4 1.8~2.5 1.8~2.5 B 0.5~0.8 0.8~1.5 0.8~1.7 0.8~1.7 C 0.6~0.8 0.9~1.2 1.2~1.6 1.8~2.5
		Type

а b С

0.5~0.6 0.3~0.4 0.15~0.25

Precautions on the use of	Multilayer Ceramic Capacitors	
Stages	Precautions	Technical considerations
		Land pattern Solder-resist
2.PCB Design		(unit: mm) (2) Examples of good and bad solder application
		Items Not recommended Recommended Mixed mounting of SMD and leaded components leaded components
		Component placement close to the chassis
		Hand-soldering of leaded components near mounted components Solder-resist Solder-resist Solder-resist Solder-resist
		Horizontal component placement
	Pattern configurations (Capacitor layout on panelized [breakaway] PC boards) 1. After capacitors have been mounted on the boards, chips	1-1. The following are examples of good and bad capacitor layout; SMD capacitors shou be located to minimize any possible mechanical stresses from board warp or deflection
	can be subjected to mechanical stresses in subsequent	Not recommended Recommended
	manufacturing processes (PCB cutting, board inspection, mounting of additional parts, assembly into the chassis, wave soldering the reflow soldered boards etc.) For this reason, planning pattern configurations and the position of SMD capacitors should be carefully performed to minimize stress.	Deflection of the board Deflection of the board Deflection of the mechanical stresses that are anticipated.
	parions sincing as surviving periodical to minimize sinces.	1-2. To layout the capacitors for the breakaway PC board, it should be noted that it amount of mechanical stresses given will vary depending on capacitor layout. The example below shows recommendations for better design.
		Perforation C D B Slit Magnitude of stress A>B = C>D>E
		1-3. When breaking PC boards along their perforations, the amount of mechanical stress on the capacitors can vary according to the method used. The following method are listed in order from least stressful to most stressful: push-back, slit, V-groovin and perforation. Thus, any ideal SMD capacitor layout must also consider the PC splitting procedure.

Stages	Precautions		Technical consider	rations
Adjustment of mounting machine Excessive impact load should not be imposed on the capacitors when mounting onto the PC boards. The maintenance and inspection of the mounters should be conducted periodically.		capacitors, cau before lowering (1) The lower limi PC board after (2) The pick-up pr (3) To reduce the nozzle, support	sing damage. To avoid this, the fithe pick-up nozzle: t of the pick-up nozzle should be correcting for deflection of the bressure should be adjusted between amount of deflection of the boring pins or back-up pins should	
		Single-sided mounting	Cracks	Supporting pin-
		Double-sided mounting	Solder peding Cracks	Supporting pin-
		cracking of the this, the monitor	capacitors because of mechanic ring of the width between the align	e nozzle height can cause chipping or al impact on the capacitors. To avoid nment pin in the stopped position, and bin should be conducted periodically.
	Selection of Adhesives 1. Mounting capacitors with adhesives in preliminary assembly, before the soldering stage, may lead to degraded capacitor characteristics unless the following factors are appropriately checked; the size of land patterns, type of adhesive, amount applied, hardening temperature and hardening period. Therefore, it is imperative to consult the manufacturer of the adhesives on proper usage and amounts of adhesive to use.	the shrinkage p stresses on the adhesive applie lowing precaution (1) Required adhe a. The adhesive sing & solder prob. The adhesive side.	percentage of the adhesive and e capacitors and lead to crackir of to the board may adversely affons should be noted in the applications characteristics chould be strong enough to hold	parts on the board during the mount- high temperatures. ekness consistency. ed shelf life. naracteristics. mission of toxic gasses.
		Figure	212/316 case size	es as examples
		a	0.3mm	min
		b	100 ~12	
		С	Adhesives should no	t contact the pad
		Amoui	nt of adhesive	After capacitors are bonded

Stages	Precautions	Technical considerations
Soldering	Selection of Flux 1. Since flux may have a significant effect on the performance of capacitors, it is necessary to verify the following conditions prior to use; (1) Flux used should be with less than or equal to 0.1 wt% (equivelent to chroline) of halogenated content. Flux having a strong acidity content should not be applied. (2) When soldering capacitors on the board, the amount of flux applied should be controlled at the optimum level. (3) When using water-soluble flux, special care should be taken to properly clean the boards.	 1-1. When too much halogenated substance (Chlorine, etc.) content is used to activate the flux, or highly acidic flux is used, an excessive amount of residue after soldering may lead to corrosion of the terminal electrodes or degradation of insulation resistance on the surface of the capacitors. 1-2. Flux is used to increase solderability in flow soldering, but if too much is applied, a large amount of flux gas may be emitted and may detrimentally affect solderability. To minimize the amount of flux applied, it is recommended to use a flux-bubbling system 1-3. Since the residue of water-soluble flux is easily dissolved by water content in the air, the residue on the surface of capacitors in high humidity conditions may cause a degradation of insulation resistance and therefore affect the reliability of the components. The cleaning methods and the capability of the machines used should also be considered carefully when selecting water-soluble flux.
	Soldering Temperature, time, amount of solder, etc. are specified in accordance with the following recommended conditions.	1-1. Preheating when soldering Heating: Ceramic chip components should be preheated to within 100 to 130°C of th soldering. Cooling: The temperature difference between the components and cleaning proces should not be greater than 100°C. Ceramic chip capacitors are susceptible to thermal shock when exposed to rapid or concer trated heating or rapid cooling. Therefore, the soldering process must be conducted wit great care so as to prevent malfunction of the components due to excessive thermal shock.
	Sn-Zn solder paste can affect MLCC reliability performance. Please contact us prior to usage.	Recommended conditions for soldering [Reflow soldering] Temperature profile Temperature (°C) Peak 280°C max Peak 280°C ma
		Preheating 200°C Prehea

Stages	Precautions	Technical considerations
4. Soldering		[Hand soldering] Temperature profile Temperature (*C) (Pb free soldering) 400 300 Preheating Preheating Over 1 minute Within 3 seconds Temperature (*C) (Pb free soldering) 300 400 400 400 400 400 400 40
5.Cleaning	Cleaning conditions 1. When cleaning the PC board after the capacitors are all mounted, select the appropriate cleaning solution according to the type of flux used and purpose of the cleaning (e.g. to remove soldering flux or other materials from the production process.) 2. Cleaning conditions should be determined after verifying, through a test run, that the cleaning process does not affect the capacitor's characteristics.	1. The use of inappropriate solutions can cause foreign substances such as flux residue to adhere to the capacitor or deteriorate the capacitor's outer coating, resulting in a degradation of the capacitor's electrical properties (especially insulation resistance). 2. Inappropriate cleaning conditions (insufficient or excessive cleaning) may detrimentally affect the performance of the capacitors. (1) Excessive cleaning In the case of ultrasonic cleaning, too much power output can cause excessive vibration of the PC board which may lead to the cracking of the capacitor or the soldered portion, or decrease the terminal electrodes' strength. Thus the following conditions should be carefully checked; Ultrasonic output Below 20 W/ & Ultrasonic frequency Below 40 kHz Ultrasonic washing period 5 min. or less
6.Post cleaning processes	1. With some type of resins a decomposition gas or chemical reaction vapor may remain inside the resin during the hardening period or while left under normal storage conditions resulting in the deterioration of the capacitor's performance. 2. When a resin's hardening temperature is higher than the capacitor's operating temperature, the stresses generated by the excess heat may lead to capacitor damage or destruction. The use of such resins, molding materials etc. is not recommended.	
7.Handling	Breakaway PC boards (splitting along perforations) 1. When splitting the PC board after mounting capacitors and other components, care is required so as not to give any stresses of deflection or twisting to the board. 2. Board separation should not be done manually, but by using the appropriate devices. Mechanical considerations 1. Be careful not to subject the capacitors to excessive mechanical shocks. (1) If ceramic capacitors are dropped onto the floor or a hard surface, they should not be used. (2) When handling the mounted boards, be careful that the mounted components do not come in contact with or bump against other boards or components.	

Stages	Precautions	Technical considerations
3.Storage conditions	Storage 1. To maintain the solderability of terminal electrodes and to keep the packaging material in good condition, care must be taken to control temperature and humidity in the storage area. Humidity should especially be kept as low as possible. Recommended conditions Ambient temperature Below 30°C Humidity Below 70% RH The ambient temperature must be kept below 40°C. Even under ideal storage conditions capacitor electrode solderability decreases as time passes, so should be used within 6 months from the time of delivery. Ceramic chip capacitors should be kept where no chlorine or sulfur exists in the air. 2. The capacitance value of high dielectric constant capacitors (type 2 &3) will gradually decrease with the passage of time, so this should be taken into consideration in the circuit design. If such a capacitance reduction occurs, a heat treatment of 150°C for 1hour will return the capacitance to its initial level.	If the parts are stored in a high temperature and humidity environment, problem such as reduced solderability caused by oxidation of terminal electrodes and deterioration of taping/packaging materials may take place. For this reason, component should be used within 6 months from the time of delivery. If exceeding the above period, please check solderability before using the capacitors.